In re Appln. of INOUE et al. Application No. Unassigned

## ABSTRACT AMENDMENTS

Replace the Abstract with:

A semiconductor device fabricating method includes-an amorphous silicon laminating process for forming an amorphous silicon film-(2) on a substrate-(1), an irradiation process for irradiating the amorphous silicon film-(2) with laser light-(16) to transform at least a part of the amorphous silicon film-(2) into a polycrystalline silicon film, and an exidation process for oxidizing the surface of the polycrystalline silicon film in an atmosphere including oxygen, after the irradiation-process. Herein, the The laser light-(16) is a linear beam having an energy-density gradient of at least 3 (mJ/cm²)/µm-or more in-the a widthwise direction, and the linear beam is generated by transforming-pulse pulsed laser light with a wavelength in a range between 350 nm-or more and 800 nm-or less. The oxidation-process is performed in-an atmosphere of a saturated water vapor-under ambient at a pressure of at least 10 atmospheric pressures or more atmospheres and at a temperature in a range between 500°C-or more and 650°C-or less. With this method, a semiconductor device with excellent crystallinity can be easily fabricated.